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| APPLICATION NO.   | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO.          | CONFIRMATION NO. |
|---|-------------|----------------------|------------------------------|------------------|
| 10/685,550  | 10/14/2003  | Wayne G. Renken      | SENS.005US1                  | 4924             |
| 36257   | 7590        | 12/23/2005           |                              |                  |
| PARSONS HSUE & DE RUNTZ LLP<br>595 MARKET STREET<br>SUITE 1900<br>SAN FRANCISCO, CA 94105 |             |                      |                              |                  |
|   |             |                      | EXAMINER<br>MEIER, STEPHEN D |                  |
|   |             |                      | ART UNIT<br>2853             | PAPER NUMBER     |

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Please find below and/or attached an Office communication concerning this application or proceeding.



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| EXAMINER |
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| ART UNIT | PAPER |
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Commissioner for Patents

The IDS filed 4/21/05 has been considered. An initialed copy of PTO 1449 is enclosed.

  
**STEPHEN MEIER**  
**SUPERVISORY PATENT EXAMINER**